

**A novel detector based on dual-mode fiber  
polished half block's characteristics for sensitive  
monitoring of radiation and materials**

**Dr. Saeed Ghadirli**

**Physics Department,**

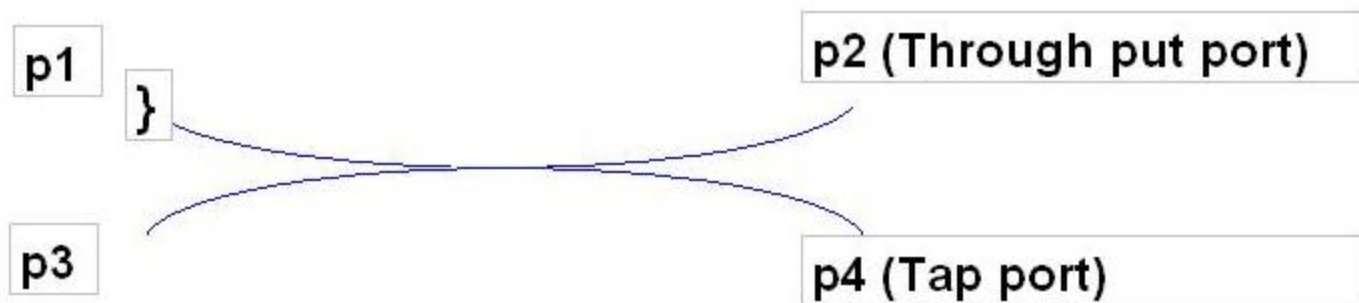
**Islamic Azad University, Noshahr-Chalus Branch,**

**Mazandaran, Chalus, Iran**

## ABSTRACT

The overlay index dependence characteristics of the power distribution between two modes of dual-mode fiber polished half blocks is studied. The heat dependence characteristics of a certain overlay index affects the modal power distributions at the input of interferometric sensors used for monitoring the sensitive heat radiation changes. The other fundamental applications, such as material recognitions through the index dependence characteristics in the closed chambers is also suggested.

# Introduction



**Loss = - 10 Log (p<sub>o</sub>/p<sub>i</sub>)**

**Through put loss = 10 log (p<sub>2</sub>/p<sub>1</sub>)**

**Tap loss = 10 log (p<sub>4</sub>/p<sub>1</sub>)**

**Directionality = 10 log (p<sub>3</sub>/p<sub>1</sub>)**

**Excess los or insersion loss = 10 log [ (p<sub>2</sub> + p<sub>4</sub>)/p<sub>1</sub> ]**

**splitting ratio or extinction ratio = 10 log (p<sub>2</sub>/p<sub>4</sub>)**

## Fiber optic polished half-blocks(PHBs)

PHBs are used as basic building blocks in many fiber optic components such as

Bergh et.al.	SMF polarizer (1980)
Digonnet et.al.	SMF directional coupler (1982)
Markatos et.al.	switch (1987)
Ghadirli et.al.	mode coupler/filter (1991)

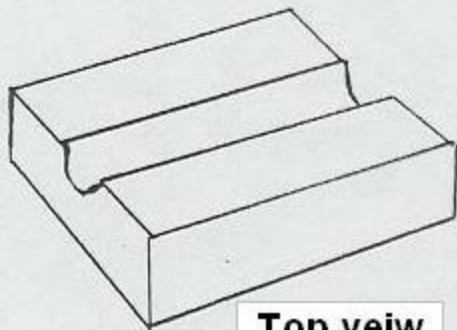
**This paper**      **As Detector**

### Transmiss depends on Characteristic of PHB

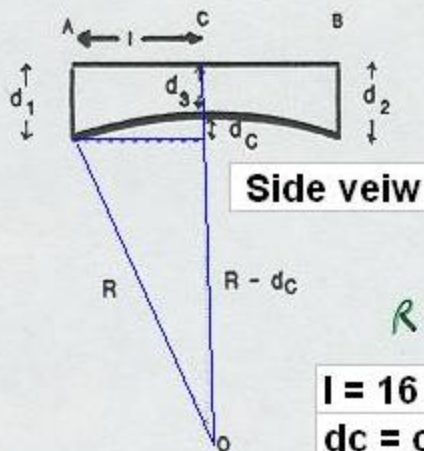
- 1- Fiber parameters
- 2- Depth of polishing
- 3- Groove radius (radius of curvature)
- 4- overlay index

**This paper**      **overlay index**





Top veiw



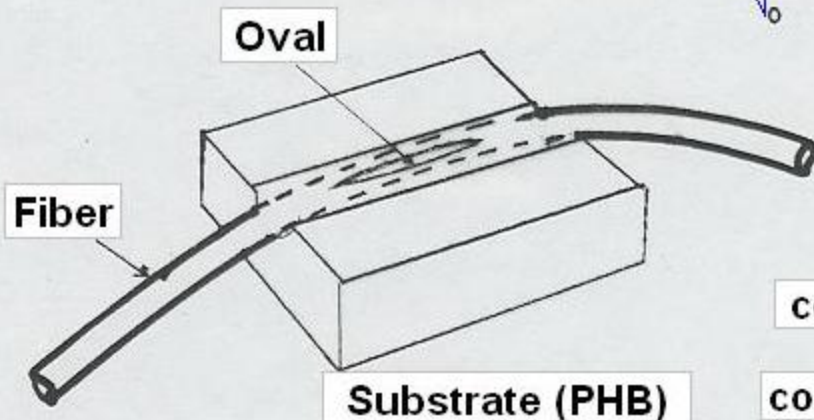
Side veiw

$$R = \frac{l^2}{2d_c}$$

$$l = 16 \text{ mm}$$

$$d_c = 0.345 \text{ mm}$$

$$R = 29.05 \text{ cm}$$



Oval

Fiber

Substrate (PHB)

corning glass technol.

core	{	$d = 4.2 \text{ micrometer}$
		$n = 1.4621$

clad	{	$d = 80.2 \text{ micrometer}$
		$n = 1.4572$

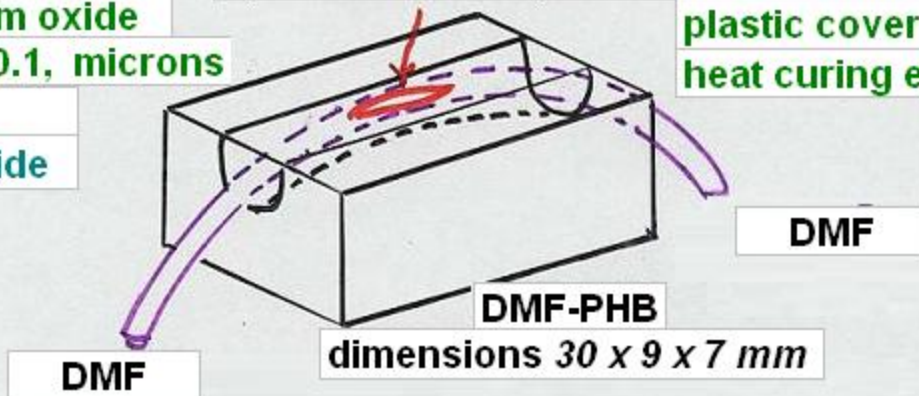
# Experimental Setups For DMF

Polished region of DMF upto 1 micron depth

Abrasive: Aluminium oxide  
grain size: 0.9, 0.5, 0.1, microns

polished by :  
0.25 Cerium oxide

plastic cover removed by  
heat curing epoxy (epotek 330)



overlay liquid

DMF

Refractive index

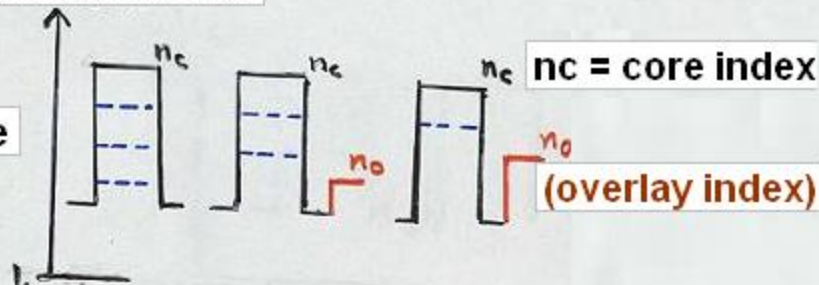
core

$n_c$  = core index

$n_o$  (overlay index)

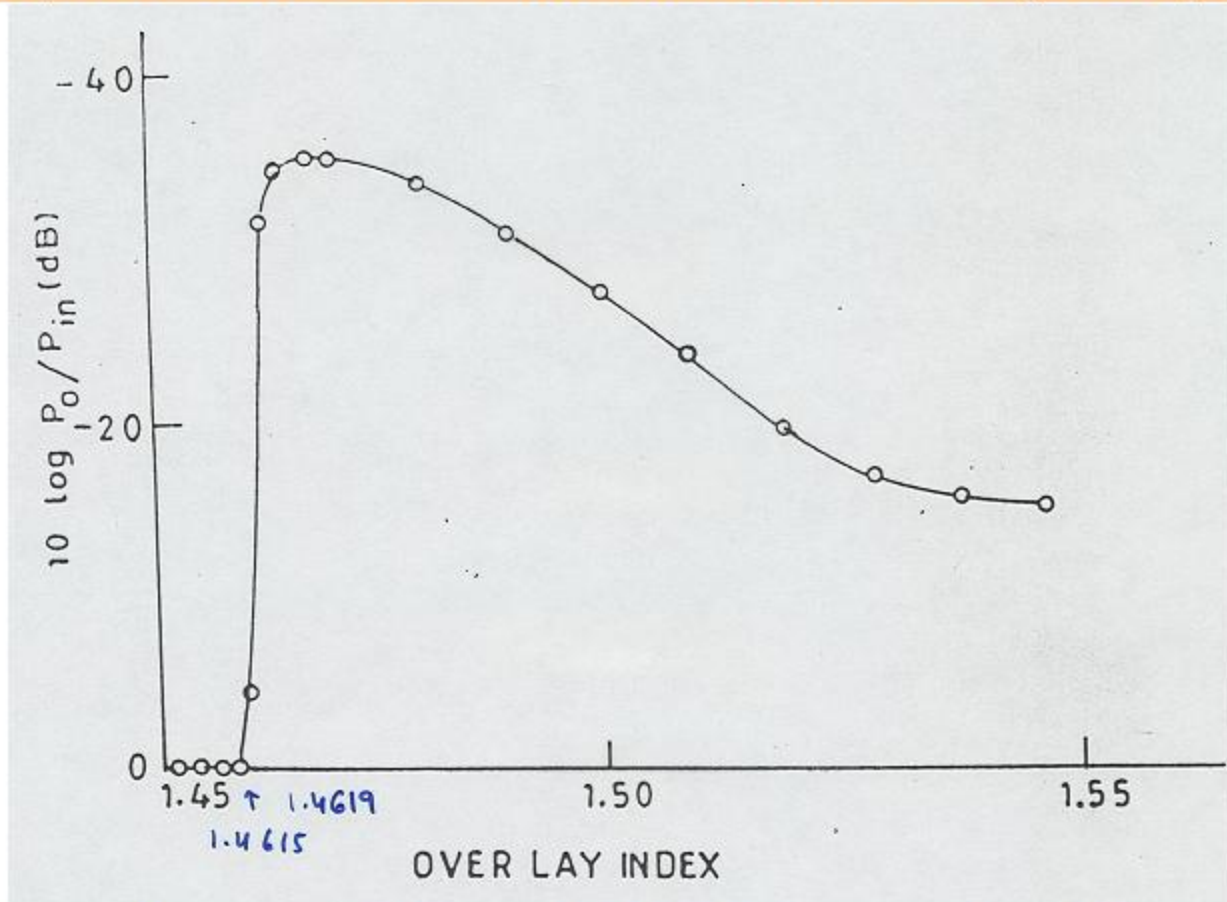
LASER

DMF-PhB



543 nanometer (green)

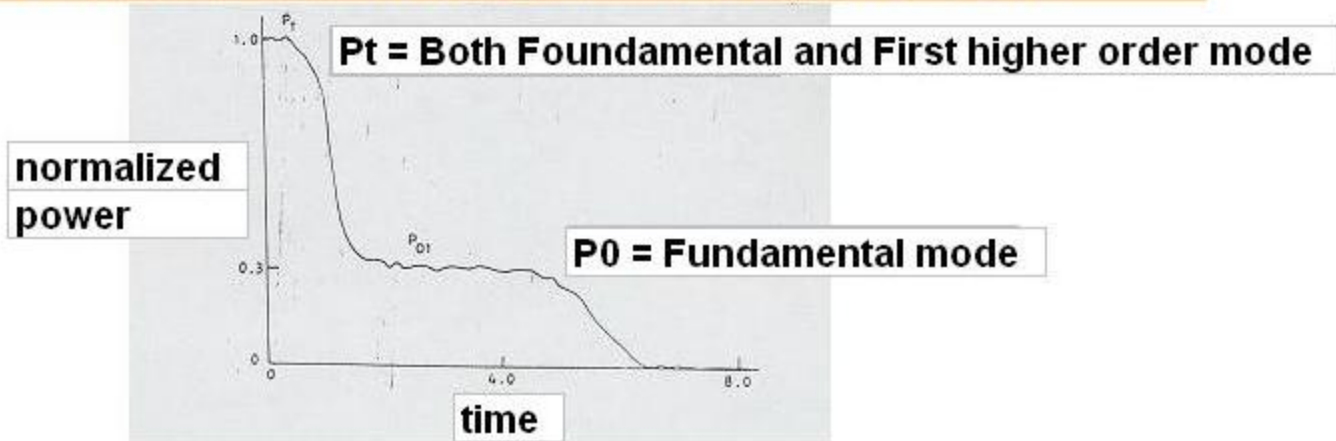
## Comparison of SMF results with that of Digonet (1982)



**Loss characteristics of SMF-PHB as a function of overlay index at wavelength = 633 nanometer**  
**Transmission loss at  $n=1.6$  was 12 dB**

**Results exactly matched i.e.**  
**Experiment was perfectly done**

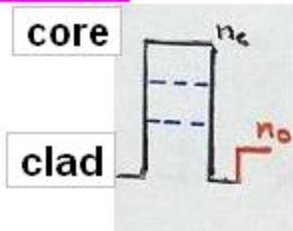
# Loss characteristics of DMF-PHB as a function of overlay index at wavelength = 543 nanometer





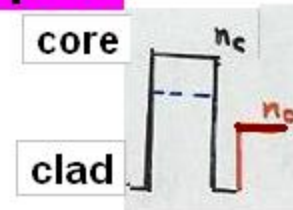
## How it works

### Step 1:



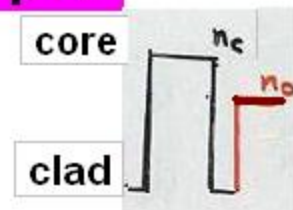
As Temperature increases  $n$  of liquid decreases  
 $n$  of liquid is below effective index of both mode  
and all power is seen at the Fiber end

### Step 2:



As Temperature drops  $n$  of liquid increases  
 $n$  of liquid is equal to effective index of LP11  
LP11 is lost through evanescent field of PHB  
only fundamental mode appears at fiber end

### Step 3:



As Temperature drops  $n$  of liquid increases  
 $n$  of liquid is equal to effective index of LP01  
LP01 is lost through evanescent field of PHB  
No power is detected at the fiber end

## Possible Applications:

For a certain initial excitation condition of the SMF-PHB with a known overlay medium with temperature dependent refractive index, SMF-PHB can be used to detect the temperature changes through its output power variation measurements. For more sensitive detection of the radiations a DMF-PHB is suggested to be used. The fundamental mode in DMF-PHB can be considered as reference arm and the temperature changing first higher order mode could serve as measurand arm at the input of an interferometric detector.

For a certain initial excitation and condition of the PHB as each overlay medium has a unique index of refraction and hence a certain output profile. Keeping the record of the refractive indices of the materials one could recognize them by comparing the profiles with the references.



## References

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**Thanks**

**Dr. S. Ghadirli**